Recent Advances in Artificial Intelligence and Deep Learning for Sensor Information Fusion

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Message from the Guest Editors

Dear Colleagues,

This Special Issue will focus on AI and deep learning for sensor information fusion.

Topics of interest include, but are not limited to:

- AI and deep learning for sensor information fusion system
- System architecture of AI sensors and multi-sensors
- Learning model for sensor information fusion
- Intelligent-based fusion techniques for multi-sensor system
- AI and deep learning for sensor fusion decision
- AI and deep learning for sensor applications
- Deep learning and machine learning for sensor message control
- Intelligent and learning-based sensor communication technology
- Learning-based fusion processing for sensor and multi-sensor system
- AI and deep learning for data mining in IoT
- AI chips for sensors, UAVs, home appliances and mobile devices

For further reading, please follow the link to the Special Issue Website at:
www.mdpi.com/journal/sensors/special_issues/Sensor_Information_Fusion
Message from the Editorial Board

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